

Notice of References Cited	Application/Control No. 10/750,168		Applicant(s)/Patent Under Reexamination FROELICH ET AL.	
	Examiner Sam K. Ahn		Art Unit 2611	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,154,871	11-2000	Claydon et al.	714/795
*	B	US-7,200,782	04-2007	Vining, Suzanne Mary	714/700
*	C	US-2002/0118738	08-2002	Whitlock, Malcolm	375/226
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Li et al. Paradigm Shift for Jitter and Noise in Design and Test > GB/s communication Systems IEEE, 2003, p.1-5
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.